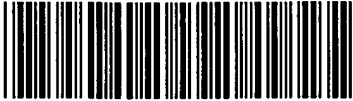


<b>Search Notes</b>  	<b>Application/Control No.</b>  10638397	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG, LIN-WEI
	<b>Examiner</b>  Kosowski, Alexander J	<b>Art Unit</b>  2125

SEARCHED			
Class	Subclass	Date	Examiner
700	90	12/20/07	AJK
361	685,727		

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search (attached)	12/20/07	AJK
EIC TC2100 PLUS Search		
Consulted Primary Examiner in AU2835 for search assistance		
PALM Inventor Name Search		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner